JOHNS HOPKINS WHITING SCHOOL of ENGINEERING

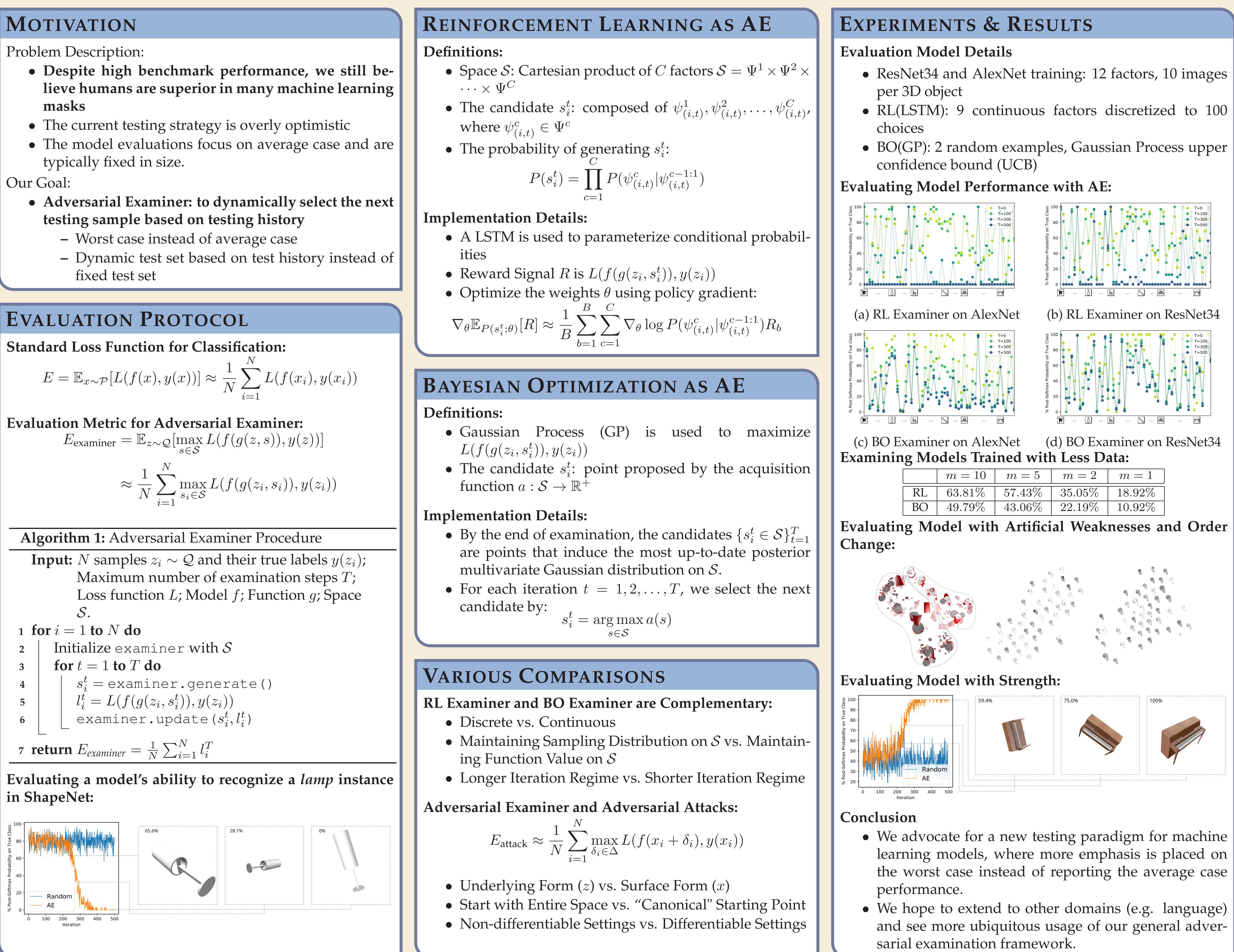
- masks
- typically fixed in size.
- - testing sample based on testing history

 - fixed test set

$$I = \mathbb{E}_{x \sim \mathcal{P}}[L(f(x), y(x))] \approx \frac{1}{N} \sum_{i=1}^{N} L(f(x_i), y(x_i))$$

$$\approx \frac{1}{N} \sum_{i=1}^{N} \max_{s_i \in \mathcal{S}} L(f(g(z_i, s_i)), y(z_i))$$

2 | Initialize examiner with
$$S$$



Identifying Model Weakness with Adversarial Examiner

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